

Search Notes**Application/Control No.**

10/665,654

Examiner

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Applicant(s)/Patent under Reexamination

CHEN ET AL.

Art Unit

2816

SEARCHED

Class	Subclass	Date	Examiner
327	261	02/17/05	LMN
4	263	4	4
4	264	4	4
6	268	4	4
6	288	4	4
11	290	4	4
365	233	4	"

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner